

<b>Notice of References Cited</b>	Application/Control No. 10/534,506	Applicant(s)/Patent Under Reexamination DELGADO ACARRETA, RAUL	
	Examiner Calvin Ma	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0038928	02-2003	Alden, Ray M.	353/122
*	B	US-2003/0032459	02-2003	Kim, Seok-Ki	455/569
*	C	US-2002/0087656	07-2002	Gargiulo et al.	709/217
*	D	US-2003/0169213	09-2003	Spero, Yechezkal Evan	345/7
*	E	US-6,977,630	12-2005	Donath et al.	345/7
*	F	US-2002/0196201	12-2002	Rosen, John B.	345/7
*	G	US-6,889,065	05-2005	Holmes et al.	455/569.2
*	H	US-5,822,023	10-1998	Suman et al.	348/837
*	I	US-5,576,687	11-1996	Blank et al.	340/438
*	J	US-6,711,543	03-2004	Cameron, Seth A.	704/270
*	K	US-2007/0146235	06-2007	Nolan et al.	345/007
*	L	US-6,300,939	10-2001	Decker et al.	345/157
*	M	US-2001/0032127	10-2001	Lewis, Lennox	705/14

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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